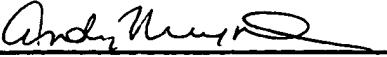


<p style="text-align: center;">CITE INFORMATION DISCLOSURE CITATION (use several sheets if necessary)</p> <p style="text-align: center;">JUN 28 2004 U.S. PATENT AND TRADEMARK OFFICE</p>			ATTY DOCKET NO. FIS920030245		SERIAL NO. 10/708,430		
			FILING DATE 3/3/04		GROUP		
U.S. PATENT DOCUMENTS							
*EXAMINER'S INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	subclass	FILING DATE IF APPROPRIATE	
Al	6,228,694	5/8/01	Doyle et al.				
	6,406,973	6/18/02	Lee				
	6,281,532	8/28/01	Doyle et al.				
	5,683,934	11/4/97	Candelaria				
	6,368,931	4/9/02	Kuhn et al.				
	5,310,446	5/10/94	Konishi et al.				
	4,853,076	8/1/89	Tsaur et al.				
	2002/0090791	7/11/02	Doyle et al.				
	2002/0074598	6/20/02	Doyle et al.				
	6,509,618	1/21/03	Jan et al.				
Al	6,476,462	11/5/02	Shimizu et al.				
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	subclass	TRANSLATION	
				YES	NO		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER			DATE CONSIDERED				
			07/20/05				
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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Ahr		6,362,082	3/26/02	Doyle et al.			
		6,228,694	5/8/01	Doyle et al.			
		5,565,697	10/15/96	Asakawa et al.			
		2003/0040158	2/27/03	Saitoh			
		2002/0086472	7/4/02	Roberds et al			
		6,521,964	2/18/03	Jan et al.			
		6,506,652	1/14/03	Jan et al.			
		5,081,513	1/14/92	Jackson et al.			
		3,602,841	8/31/71	McGroddy			
		6,531,740	3/11/03	Bosco et al.			
Ahr		6,531,369	3/11/03	Ozkan et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES
							NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER				DATE CONSIDERED			
<i>Andy, Kuy</i>				07/20/05			

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Ali</i>	6,501,121	12/31/02	Yu et al.			
	6,498,358	12/24/02	Lach et al.			
	6,493,497	12/10/02	Ramdani et al.			
	6,403,975	6/11/02	Brunner et al.			
	6,361,885	3/26/02	Chou			
	6,255,169	7/3/01	Li et al.			
	6,246,095	6/12/01	Brady et al.			
	6,165,383	12/26/00	Chou			
	6,133,071	10/17/00	Nagai			
	6,046,464	4/4/00	Schetzina			
<i>Ali</i>	6,025,280	2/15/00	Brady et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Al</i>	5,940,736	8/17/99	Brady et al.				
	5,880,040	3/9/99	Sun et al.				
	5,861,651	1/19/99	Brasen et al.				
	5,679,965	10/21/97	Schetzina				
	5,670,798	9/23/97	Schetzina				
	5,561,302	10/1/96	Candelaria				
	5,471,948	12/5/95	Burroughes et al.				
	5,459,346	10/17/95	Asakawa et al.				
	5,391,510	2/21/95	Hsu et al.				
	5,371,399	12/6/94	Burroughes et al.				
<i>Al</i>	5,108,843	4/28/92	Ohtaka et al.				
FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY		CLASS	SUBCLASS	TRANSLATION	
						YES	NO
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Alh</i>	5,060,030	10/22/91	Hoke			
	4,958,213	9/18/90	Eklund et al.			
	4,665,415	5/12/87	Esaki et al.			
	5,989,978	11/23/99	Peidous			
	6,284,626	9/4/01	Kim			
	6,274,444	8/14/01	Wang			
	6,261,964	7/17/01	Wu et al.			
	6,221,735	4/24/01	Manley et al.			
	6,117,722	9/12/00	Wuu et al.			
	6,107,143	8/22/00	Park et al.			
<i>Alh</i>	6,090,684	7/18/00	Ishitsuka et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				ATTY DOCKET NO. FIS920030245		SERIAL NO. 10/708,403	
				FILING DATE 3/3/04		GROUP	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
Alv	6,066,545	5/23/00	Doshi et al.				
	6,008,126	12/28/99	Leedy				
	5,946,559	8/31/99	Leedy				
	5,840,593	11/24/98	Leedy				
	5,592,018	1/7/97	Leedy				
	5,592,007	1/7/97	Leedy				
	5,571,741	11/5/96	Leedy				
	5,557,122	9/17/96	Shrivastava et al.				
	5,354,695	10/11/94	Leedy				
	5,134,085	7/28/92	Gilgen et al.				
Alv	5,006,913	4/9/91	Sugahara et al.				
FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
					YES	NO	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER	<i>Andy Nguyen</i>			DATE CONSIDERED	07/26/05		

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				FILING DATE 3/3/04	GROUP		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Ah</i>		4,952,524	8/28/90	Lee et al.			
		4,855,245	8/8/89	Neppel et al.			
		2002/0086497	7/4/02	Kwok			
		5,960,297	9/28/99	Sakai			
		6,403,486	6/11/02	Lou			
		6,284,623	9/4/01	Zhang et al.			
		2003/0032261	2/13/03	Yeh et al.			
		2003/0057184	3/27/03	Yu et al.			
		6,265,317	7/24/01	Chiu et al.			
		2003/0067035	4/10/03	Tews et al.			
<i>Ah</i>		6,461,936	10/8/02	von Ehrenwall			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>Andy Nease</i>				DATE CONSIDERED 07/20/05			

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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Ah		6,319,794	11/20/01	Akatsu et al.			
Ah		20010009784	7/26/01	Ma et al.			
FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER		DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>Andy Kuan</i>				DATE CONSIDERED 07/20/05			
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Supplemental Form PTO-1449 (Modified)	Attorney Docket No.: FIS920030245US1	Serial No.: 10/708,430
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		31 P E
(Use several sheets if necessary)	Applicant: Michael P. Belyansky, et al.	JUN 28 2004 RECEIVED U.S. PATENT AND TRADEMARK OFFICE
Page 1 of 1	Filing Date: 3/3/04	Group:

REFERENCE DESIGNATION

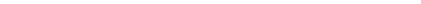
U.S. PATENT DOCUMENTS

EXAMINERS INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)

FOREIGN PATENT DOCUMENTS

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<i>Ah</i>		Kern Rim, et al., "Transconductance Enhancement in Deep Submicron Strained-Si <i>n</i> -MOSFETs", International Electron Devices Meeting, 26, 8, 1, IEEE, September 1998.
		Kern Rim, et al., "Characteristics and Device Design of Sub-100 nm Strained Si N- and PMOSFETs", 2002 Symposium On VLSI Technology Digest of Technical Papers, IEEE, pp 98-99.
		Gregory Scott, et al., "NMOS Drive Current Reduction Caused by Transistor Layout and Trench Isolation Induced Stress", International Electron Devices Meeting, 34, 4, 1, IEEE, September 1999.
		F. Ootsuka, et al., "A Highly Dense, High-Performance 130nm node CMOS Technology for Large Scale System-on-a-Chip Application", International Electron Devices Meeting, 23, 5, 1, IEEE, April 2000.
		Shinya Ito, et al., "Mechanical Stress Effect of Etch-Stop Nitride and its Impact on Deep Submicron Transistor Design", International Electron Devices Meeting, 10, 7, 1, IEEE, April 2000.
		A. Shimizu, et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement", International Electron Devices Meeting, IEEE, March 2001.
<i>Ah</i>		K. Ota, et al., "Novel Locally Strained Channel Technique for high Performance 55nm CMOS", International Electron Devices Meeting, 2, 2, 1, IEEE, February 2002.

EXAMINER	DATE CONSIDERED
	57 to 105

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